# 2SB1209

# Silicon PNP triple diffusion planar type

## For low-frequency amplification

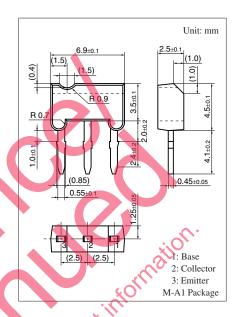
#### ■ Features

- High collector-base voltage (Emitter open) V<sub>CBO</sub>
- ullet High collector-emitter voltage (Base open)  $V_{CEO}$
- ullet Low collector-emitter saturation voltage  $V_{\text{CE(sat)}}$

## ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	-400	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-400	V	
Emitter-base voltage (Collector open)	$V_{EBO}$	-5	V	
Collector current	$I_C$	-100	mA	
Peak collector current	$I_{CP}$	-200	mA	
Collector power dissipation *	P <sub>C</sub>	1	W	
Junction temperature	T <sub>j</sub>	150	°C	
Storage temperature	T <sub>stg</sub>	-55 to +150	°C	

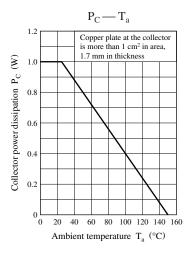
Note) \*: Print circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion

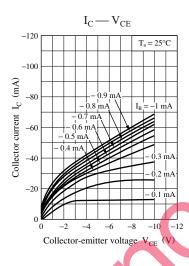


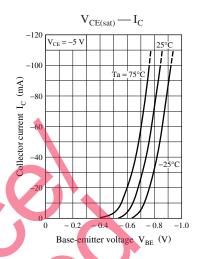
## ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

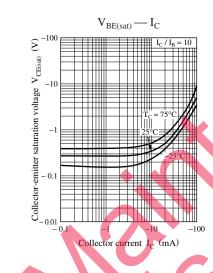
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	$I_{\rm C} = -100  \mu A, I_{\rm B} = 0$	-400			V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_{\rm C} = 500 \mu{\rm A}, I_{\rm B} = 0$	-400			V
Emitter-base voltage (Collector open)	$V_{EBO}$	$I_{\rm E} = -100 \mu{\rm A},  I_{\rm C} = 0$	-5			V
Forward current transfer ratio	h <sub>FE</sub>	$V_{CE} = -5 \text{ V}, I_{C} = -30 \text{ mA}$	40			_
Collector-emitter saturation voltage	VE(sat)	$I_C = -10 \text{ mA}, I_B = -1 \text{ mA}$			- 0.6	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	$I_C = -50 \text{ mA}, I_B = -5 \text{ mA}$			-1.5	V
Transition frequency	$f_T$	$V_{CB} = -30 \text{ V}, I_E = 20 \text{ mA}, f = 200 \text{ MHz}$		50		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -30 \text{ V}, I_E = 0, f = 1 \text{ MHz}$			9	pF
(Common base, input open circuited)						

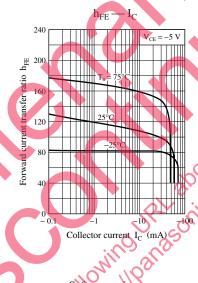
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

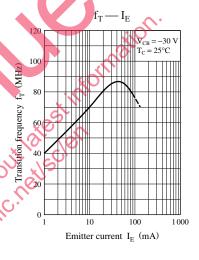


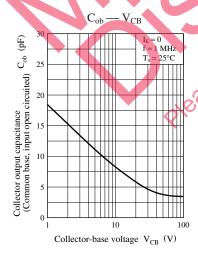


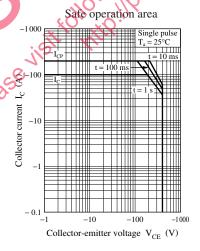












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